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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/567,250	01/05/2007	Michio Watanabe	1794-0179PUS1	3050
	7590 10/08/200 ART KOLASCH & BI	EXAMINER		
PO BOX 747			DOYLE, JOHN	
FALLS CHURCH, VA 22040-0747			ART UNIT	PAPER NUMBER
			2891	
			NOTIFICATION DATE	DELIVERY MODE
			10/08/2009	ELECTRONIC

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Notice of the Office communication was sent electronically on above-indicated "Notification Date" to the following e-mail address(es):

mailroom@bskb.com

	Application No.	Applicant(s)			
	10/567,250	WATANABE ET AL.			
Office Action Summary	Examiner	Art Unit			
	JOHN DOYLE	2891			
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the c	orrespondence address			
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING DA - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period v - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tim vill apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONEI	N. nely filed the mailing date of this communication. D (35 U.S.C. § 133).			
Status					
Responsive to communication(s) filed on <u>28 Jules</u> This action is FINAL . 2b)⊠ This Since this application is in condition for alloware closed in accordance with the practice under E	action is non-final. nce except for formal matters, pro				
Disposition of Claims					
4) Claim(s) 1-9 is/are pending in the application. 4a) Of the above claim(s) 6-9 is/are withdrawn for the specification is/are allowed. 5) Claim(s) is/are allowed. 6) Claim(s) 1-5 is/are rejected. 7) Claim(s) is/are objected to. 8) Claim(s) are subject to restriction and/or are subject to restriction and/or are subjected to by the Examine 10) The specification is objected to by the Examine 10) The drawing(s) filed on is/are: a) access Applicant may not request that any objection to the specification are specification are specification to the specification are specification are specification to the specification are specification to the specification are specific	r election requirement. r. epted or b)⊡ objected to by the B drawing(s) be held in abeyance. See	e 37 CFR 1.85(a).			
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d). 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.					
Priority under 35 U.S.C. § 119					
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 					
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date 2/6/2006.	4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal P 6) Other:	nte			

DETAILED ACTION

Election/Restrictions

Claims 6-9 are withdrawn from further consideration pursuant to 37 CFR 1.142(b), as being drawn to a nonelected micro tunnel-junction circuit, there being no allowable generic or linking claim. Applicant timely traversed the restriction (election) requirement in the reply filed on 28 July 2009.

Applicant's election with traverse of claims 1-5 in the reply filed on 28 July 2009 is acknowledged. The traversal is on the ground(s) that the inventions must be independent or distinct as claimed; and there must be serious burden on the Examiner if the Restriction is not required. This is not found persuasive because the product as claimed can be made by another and materially different process; specifically, the narrow wall formed by a focused ion beam can be alternatively formed by an electron beam lithography.

The requirement is still deemed proper and is therefore made FINAL.

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Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

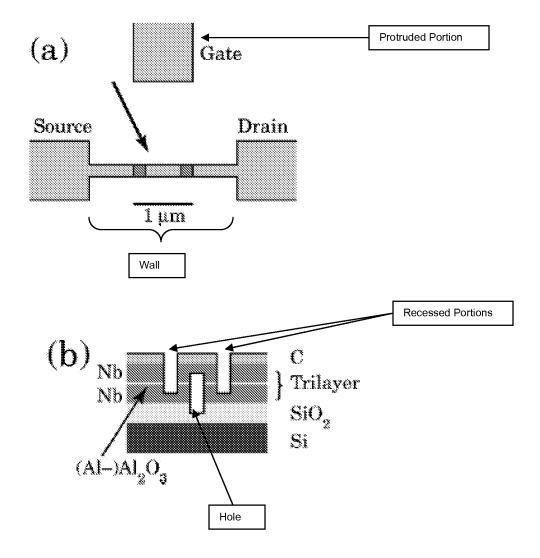
A person shall be entitled to a patent unless -

(a) the invention was known or used by others in this country, or patented or described in a printed publication in this or a foreign country, before the invention thereof by the applicant for a patent.

Claim 1 is rejected under 35 U.S.C. 102(a) as being anticipated by Watanabe et al. (Applied Physics Letters, Vol. 84, No. 3, 19 January 2004)

In re claim 1, Watanabe et al. disclose a method of manufacturing a micro tunnel-junction circuit, said method comprising the steps of: forming a three-layer structure (Fig. 1(b), i.e., Trilayer) by laminating a first metal (i.e., Nb), an insulator (i.e., Al₂O₃), and a second metal (i.e., Nb) on a substrate (i.e., SiO₂/Si) in this order; forming a narrow wall (as shown below, Fig. 1 (a)) part by milling said three-layer structure in the depth direction by using a focused ion beam (Page 410); and forming at least one laterally passed through-hole (as shown below, Fig. 1 (b)) in said wall part by using the focused ion beam (Page 410), and forming at least one recessed portion (as shown below, Fig. 1 (b)) positioned adjacent to said hole by milling the upper surface of said wall part in the depth direction, wherein said hole is a through-hole starting at the position of the head of the second metal to the position of the head of said structure, said recessed portion is formed to be recessed from the upper surface of said wall part into the first metal.

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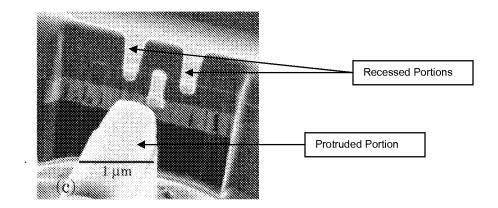
In re claim 2, Watanabe et al. disclose a method of manufacturing a micro tunnel-junction circuit, said method comprising the steps of: firming a three-layer structure (Fig. 1 (b), i.e., Trilayer) by laminating a first metal (i.e., Nb), an insulator (i.e., Al₂O₃), and a second metal (i.e., Nb) on a substrate (SiO₂/Si) in this order; forming a narrow wall (as shown above, Fig. 1 (a)) part by milling said three-layer structure in the depth direction by using a focused ion beam (Page 410); and forming a laterally passed through-hole

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(as shown above, Fig. 1 (b)) in said wall part by using the focused ion beam (Page 410), and forming two recessed portions (as shown above, Fig. 1 (b)) positioned adjacent to said hole so as to sandwich said hole by milling (Page 410) the upper surface of said wall part in the depth direction, wherein said hole is a through-hole starting at the position of the head of the second metal to the position of the head of said substrate, and said two recessed portions are formed to be recessed from the upper surface of said wall part into the first metal.

In re claim 3, Watanabe et al. disclose a method, further comprising: forming a protruded portion (as shown below, Fig. 1 (c)) by milling (i.e., focused ion beam) said three-layer structure in the depth direction by using the focused ion beam at a position adjacent to said wall and facing said hole and said two recessed portions.



In re claim 4, Watanabe et al. disclose a method, wherein said first metal and said second metal are niobium (as shown above, Fig. 1 (b)).

In re claim 5, Watanabe et al. disclose a method, wherein xenon fluoride gas is introduced when processing is performed by using said focused ion beam (Page 412).

Any inquiry concerning this communication or earlier communications from the

examiner should be directed to JOHN DOYLE whose telephone number is (571)270-

7879. The examiner can normally be reached on Monday-Thursday 7:30 AM-6:00PM,

EST.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Kiesha Rose can be reached on (571)272-1844. The fax phone number for

the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the

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JOHN DOYLE Examiner

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/Kiesha R. Bryant/

Supervisory Patent Examiner, Art Unit 2891